Performance Enhancement of Nb₃Sn **Superconductors by Artificial Pinning Centres**

<u>S. Pfeiffer¹</u>, J. Bernardi,¹ M. Stöger-Pollach¹, T. Baumgartner², M. Ortino², M. Eisterer², M. Sumption³, X. Xu⁴, X. Peng⁵, A. Ballarino⁶, S. C. Hopkins⁶, Jack Haley⁷

¹USTEM, TU Wien, Vienna, Austria, ²Atominstitut, TU Wien, Vienna, Austria, ³Center for Supercond. and Magnetic Materials, The Ohio State University, Columbus, USA, ⁴Fermi National Accelerator Lab., Batavia, USA, ⁵Hyper Tech Research Incorporated, Columbus, USA, ⁶CERN, Geneva, Switzerland, ⁷Department of Materials, University of Oxford, Oxford, UK

Introduction

Presently available state-of-the-art Nb₃Sn wires have not yet reached the required FCC performance, which heavily depends on the microstructure. New manufacturing techniques aim to push the material further to its limits through grain refinement and pinning enhancement by the introduction of artificial pinning centres (APCs).

novel manufacturing technique based on internal oxidation and formation of nano-precipitates, while the other relies on the introduction of **defects by fast neutron irradiation**.

The influence of the resulting microstructure on the superconducting



Contact: stephan.pfeiffer@tuwien.ac.at

In this study, two approaches that recently managed to achieve the FCC target critical current density are presented. One revolves around a

properties was examined through combined microstructural and magnetic analysis: by means of Transmission Electron Microscopy, **Scanning Hall Probe Microscopy and SQUID magnetometry.**

Grain Refinement by Internal Oxidation

Artificial Defects by Fast Neutron Irradiation

- Irradiation of wires in neutron reactor
- J_c increase of 50% in irradiated wires





- Internal oxidation method produces nano-precipitates by the addition of Zr or Hf
- Precipitates serve as nucleation centres for grain boundaries
- Grain refinement leads to increase in J_c



- Preparation of thin lamellae using Focused Ion Beam (FIB)
- Investigation of neutron impact sites using Transmission Electron Microscopy (TEM)



- Analysis by bright field, dark field, weak beam dark field and high resolution TEM
- Structure factor contrast and strain contrast due to deformed lattice





- Analysis of precipitates by Scanning Transmission Electron Microscopy (STEM)
- Precipitate size of around 5 20 nm



- Grain size analysis by Transmission Kikuchi Diffraction (TKD)
- APC wires show clear reduction in grain size compared to standard wires

Neutron irradiation leads to disordered regions of a few nm



